Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/837,877	YAMAZAKI ET AL.	
Examiner	Art Unit	
Monica Lewis	2822	

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257	57,59, 66,288, 347,350, 351	3/27/2006	ML

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEAF (INCLUDING S	RCH NOTES		)
		DATE	EXMR
East Search	3	/27/2006	ML
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